



EMC COMPLIANCE TEST REPORT

for

3U-sized Pentium MMX CPU module for Compact PCI

Trade Name : ADVANTECH
Model Number : MIC-3351 ; MIC-3351S
Serial Number : Prototype
Report Number : 990405-E
Date : September 18, 1999
Regulations : See below

Standards	Results (Pass/Fail)
EN 550022: 1994 (Class A)	PASS
EN 61000-3-2 :1995	PASS
EN 61000-3-3 :1995	PASS
EN 50082-2: 1995	PASS
-EN 61000-4-2: 1995	PASS
-EN 61000-4-4: 1996	PASS
-EN 61000-4-5: 1995	PASS
-EN 61000-4-11: 1994	PASS
-ENV 50140: 1994	PASS
-ENV 50204: 1996	PASS
-ENV 50141: 1994	PASS

Prepared for :

Advantech Co., Ltd.
4th FL., No. 108-3, Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.

Prepared by :

C & C Laboratory Co., Ltd.
1st Fl., No. 344, Fu Ching Street
Taipei, Taiwan, R.O.C.

TEL: (02)27468584
FAX: (02)27632154



This report shall not be reproduced, except in full, without the written approval of
C&C Laboratory Co., Ltd.



EC-Declaration of Conformity

For the following equipment:

3U-sized Pentium MMX CPU module for Compact PCI

(Product Name)

MIC-3351 ; MIC-3351S / ADVANTECH

(Model Designation / Trade name)

Advantech Co., Ltd.

(Manufacturer Name)

4th FL., No. 108-3, Ming-Chuan Road, Hsin-Tien City, Taipei Hsien, Taiwan, R.O.C.

(Manufacturer Address)

is herewith confirmed to comply with the requirements set out in the Council Directive on the Approximation of the Laws of the Member States relating to Electromagnetic Compatibility Directive (89/336/EEC, Amended by 92/31/EEC & 93/68/EEC). For the evaluation regarding the Electromagnetic Compatibility (89/336/EEC, Amended by 92/31/EEC & 93/68/EEC), the following standards are applied:

<input type="checkbox"/> EN 50081-2:1993	<input checked="" type="checkbox"/> ENV 50140: 1994	<input checked="" type="checkbox"/> EN 61000-4-2: 1995	<input checked="" type="checkbox"/> EN 61000-3-2: 1995
<input checked="" type="checkbox"/> EN 50082-2:1995	<input checked="" type="checkbox"/> ENV 50141: 1994	<input type="checkbox"/> EN 61000-4-3: 1995	<input checked="" type="checkbox"/> EN 61000-3-3:1995
<input checked="" type="checkbox"/> EN 55022:1994 (Class A)	<input checked="" type="checkbox"/> ENV 50204: 1996	<input checked="" type="checkbox"/> EN 61000-4-4: 1995	
<input checked="" type="checkbox"/> EN 61000-4-5: 1995	<input type="checkbox"/> EN 61000-4-6: 1995	<input checked="" type="checkbox"/> EN 61000-4-11: 1994	

The following manufacturer / importer or authorized representative established within the EUT is responsible for this declaration:

(Company Name)

(Company Address)

Person responsible for making this declaration:

(Name, Surname)

(Position / Title)

(Place)

(Date)

(Legal Signature)

TABLE OF CONTENTS

DESCRIPTION	PAGE
VERIFICATION OF COMPLIANCE	5
GENERAL INFORMATION	6
SYSTEM DESCRIPTION	7
PRODUCT INFORMATION	8
SUPPORT EQUIPMENT	9
TEST FACILITY	10
TEST EQUIPMENT	11
SECTION 1 EN 55022 (LINE CONDUCTED & RADIATED EMISSION)	15
MEASUREMENT PROCEDURE & LIMIT (LINE CONDUCTED EMISSION TEST)	15
MEASUREMENT PROCEDURE & LIMIT (RADIATED EMISSION TEST)	17
BLOCK DIAGRAM OF TEST SETUP	20
SUMMARY DATA	21
SECTION 2 EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS & VOLTAGE FLUCTUATION/FLICKER)	24
BLOCK DIAGRAM OF TEST SETUP	25
TEST RESULT	25
SECTION 3 EN 61000-4-2 (ELECTROSTATIC DISCHARGE)	26
BLOCK DIAGRAM OF TEST SETUP	27
TEST PROCEDURE	28
PERFORMANCE & RESULT	28
ESD TESTED POINT TO EUT	29
SECTION 4 ENV 50140 (RADIATED ELECTROMAGNETIC FIELD)	30
BLOCK DIAGRAM OF TEST SETUP	30
TEST PROCEDURE	31
PERFORMANCE & RESULT	31

DESCRIPTION	PAGE
SECTION 5 ENV 50204 (RADIATED ELECTROMAGNETIC FIELD FROM DIGITAL TELEPHONES)	32
BLOCK DIAGRAM OF TEST SETUP	32
TEST PROCEDURE	33
PERFORMANCE & RESULT	33
SECTION 6 EN 61000-4-4 (FAST TRANSIENTS/BURST)	34
BLOCK DIAGRAM OF TEST SETUP	34
TEST PROCEDURE	35
PERFORMANCE & RESULT	35
SECTION 7 ENV 50141 (CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS)	36
BLOCK DIAGRAM OF TEST SETUP	36
TEST PROCEDURE	37
PERFORMANCE & RESULT	37
SECTION 8 EN 61000-4-5 (SURGE IMMUNITY)	38
BLOCK DIAGRAM OF TEST SETUP	38
TEST PROCEDURE	39
PERFORMANCE & RESULT	39
SECTION 9 EN 61000-4-11 (VOLTAGE DIP/INTERRUPTION)	40
BLOCK DIAGRAM OF TEST SETUP	40
TEST PROCEDURE	41
PERFORMANCE & RESULT	41
APPENDIX 1 PHOTOGRAPHS OF TEST SETUP EN 55022 TEST EN 61000-3-2 TEST EN 61000-3-3 TEST EN 61000-4-2 TEST ENV 50140 & ENV 50204 TEST EN 61000-4-4 TEST ENV 50141 TEST EN 61000-4-5 TEST EN 61000-4-11 TEST	42
APPENDIX 2 PHOTOGRAPHS OF EUT	52

VERIFICATION OF COMPLIANCE

Equipment Under Test: 3U-sized Pentium MMX CPU module for Compact PCI
Trade Name: ADVANTECH
Model Number: MIC-3351 ; MIC-3351S
Serial Number: Prototype
EUT Powered during test: 230VAC/50Hz
Applicant: **Advantech Co., Ltd.**
4th FL., No. 108-3, Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.
Manufacturer: **Advantech Co., Ltd.**
4th FL., No. 108-3, Ming-Chuan Road, Hsin-Tien City,
Taipei, Hsien, Taiwan, R.O.C.
Type of Test: EMC Directive 89/336/EEC for CE Marking
Technical Standards: EN 55022: 1994 / A1:1995 / A2: 1997 ClassA
EN61000-3-2: 1995, EN 61000-3-3: 1995
EN 50082-2: 1995 (EN 61000-4-2: 1995, ENV 50140,
EN 61000-4-4: 1995, EN 61000-4-5: 1995,
EN 61000-4-11: 1994, ENV 50204: 1995
ENV 50141)
File Number: 990405-E
Date of test: September 14-16, 1999
Tested by: Tony Tsai
Deviation: N/A
Condition of Test Sample: Normal

The above equipment was tested by C&C Laboratory Co., Ltd. for compliance with the requirements set forth in EMC Directive 89/336/EEC and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Approved by Authorized Signatory: Kurt Chen
Kurt Chen / Q.A. Manager

GENERAL INFORMATION

Applicant: Advantech Co., Ltd.
4th FL., No. 108-3, Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C

Contact Person: John Chou

Phone Number: (02)22184567 ext.293

Fax Number: (02)22180045

Manufacturer: Advantech Co., Ltd.
4th FL., No. 108-3, Ming-Chuan Road, Hsin-Tien City,
Taipei, Hsien, Taiwan, R.O.C.

File Number: 990405-E

Date of Test: September 14-16, 1999

Equipment Under Test: 3U-sized Pentium MMX CPU module for Compact PCI

Model Number: MIC-3351 ; MIC-3351S

Serial Number: Prototype

Technical Standards: EN 55022: 1994 / A1:1995 / A2: 1997 ClassA
EN61000-3-2: 1995, EN 61000-3-3: 1995
EN 50082-2: 1995 (EN 61000-4-2: 1995, ENV 50140,
EN 61000-4-4: 1995, EN 61000-4-5: 1995,
EN 61000-4-11: 1994, ENV 50204: 1995
ENV 50141)

**Frequency Range
(EN 55022):** 150kHz to 30MHz for Line Conducted Test
30MHz to 1000MHz for Radiated Emission Test

Test Site **C & C LABORATORY CO., LTD.**
No. 15, 14 Lin, Chi Twu Chi, Lu-Chu Hsiang
Taoyuan, Taiwan, R. O. C.

SYSTEM DESCRIPTION

EUT Test Program:

1. An EMI test software was loaded and executed under Windows environment.
2. The EMI test program sequentially exercised all I/O's of EUT.
3. A communicated software was loaded and executed to communicate between EUT and remote side.
4. The EUT sends and receives message from remote side, and filling the screen of monitor with upper case of "H" patterns.
5. Repeat step 2 to 4 throughout the test.

PRODUCT INFORMATION

Housing Type: None

EUT Power Rating: VDC from power supply

AC Power during Test 230VAC/50Hz to power supply

Power Supply Manufacturer: Win-TACT

Power Supply Model Number: WP602S22

AC Power Cord Type: Shielded, 1.8m (Detachable)

DC Power Cable Type: None

CPU Manufacturer: Intel **Model:** Pentium 266MHz

OSC/Clock Frequencies : 66MHz

Backplane Manufacturer: Advantech **Model:** MIC-3401

Chassis Manufacturer: Advantech **Model:** MIC-3001/8

SCSI card Manufacturer: Advantech **Model:** MIC-3640

I/O PORT TYPES	Q'TY	TESTED WITH
1). Serial Port	2	2
2). Video Ports	1	1
3). LAN Port	1	1
4). USB Port	2	2
5). SCSI Ports	2	2
6). PS/2 K/B port	1	1

Note: Difference between MIC-3351 and MIC-3351S is MIC-3351S has a SCSI interface and MIC-3351 hasn't.

SUPPORT EQUIPMENT

Equipment	Model #	Serial #	FCC ID	Manufacturer	Data Cable	Power Cord
Monitor	D2835	KR74011499	A3LCGE750	HP	Shielded, 1.6m	Unshielded, 1.8m
Modem	2400	94-364-176270	DK467GSM24	Computer Peripherals	Shielded, 1.8m	Unshielded, 1.8m
Modem	2400	94-364-176267	DK467GSM24	Computer Peripherals	Shielded, 1.8m	Unshielded, 1.8m
PS/2 Keyboard	K288	H803151754	FKD46AK288	Genuine	Shielded, 1.8m with a core	N/A
USB Mouse	M-BB48	LZE92400924	FDD DOC	LOGITECH	Shielded, 1.8m	N/A
USB Mouse	M-BB48	LZE92250259	FDD DOC	LOGITECH	Shielded, 1.8m	N/A
External SCSI HDD	2.1S, 3.2S, 4.3S, 6.4S	61038360	N/A	Quantum	Shielded, 1.0m	Shielded, 1.0m
External SCSI HDD	DCAS-34330	N/A	N/A	IBM	Shielded, 1.8m	Shielded, 1.8m
Mouse (Remote)	MSAH	N/A	N/A	LOGITECH	Shielded, 1.4m	N/A
Keyboard (Remote)	6311-C4C	N/A	N/A	ACER	Shielded, 1.8m	N/A
Monitor (Remote)	KM511	N/A	N/A	SAMPO	Shielded, 1.8m	Shielded, 1.8m
PC (Remote)	N/A	SG73301987	N/A	HP	Unshielded, 6m	Shielded, 1.8m

Note: All the above equipment and cables were placed in worse case positions to maximize emission signals.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

TEST FACILITY (EN 55022)

Location:	No. 15, 14 Line, Chin Twu Chi, Lu Chu Hsiang, Taoyuan, Taiwan, R.O.C.
Description:	There are three 3/10m open area tests site and three line conducted labs for final test, and one 3/10m open area test site for engineering lab. The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4:1992 and CISPR 22/EN 55022 requirements.
Site Filing:	<p>A site description is on file with the Federal Communications Commission, 7435 Oakland Mills Road, Columbia, MD 21046.</p> <p>Registration also was made with Voluntary Control Council for Interference (VCCI).</p> <p>Site is also approved by Ministry of Commerce of New Zealand.</p>
Site Accreditation:	<p>Accredited by NEMKO (Authorization #: ELA 124) for EMC & A2LA (Certificate #: 824.01) for Emission.</p> <p>Also accredited by BCIQ for the product category of Information Technology Equipment.</p>
Instrument Tolerance:	All measuring equipment is in accord with ANSI C63.4 and CISPR 22 requirement that meet industry regulatory agency and accreditation agency requirement.
Ground Plane:	Two conductive reference ground planes were used during the Line Conducted Emission, one in vertical and the other in horizontal. The dimensions of these ground planes are as below. The vertical ground plane was placed distancing 40 cm to the rear of the wooden test table on where the EUT and the support equipment were placed during test. The horizontal ground plane projected 50 cm beyond the footprint of the EUT system and distanced 80 cm to the wooden test table. For Radiated Emission Test, one horizontal conductive ground plane extended at least 1m beyond the periphery of the EUT and the largest measuring antenna, and covered the entire area between the EUT and the antenna. It has no holes or gaps having longitudinal dimensions larger than one-tenth of a wavelength at the highest frequency of measurement up to 1GHz.
Site #1 & Site #3 Line Conducted Test Site:	Vertical ground plane (2.2m x 2.2m) Horizontal ground plane (2.5m x 2.5m)
Site #4 Line Conducted Test Site:	At Shielding room

TEST EQUIPMENT

MEASURING INSTRUMENT SETTING

TEST TYPE	DETECTOR	FREQUENCY RANGE	RESOLUTION BANDWIDTH	VIDEO BANDWIDTH
Conducted	Peak/QP/Avg	150kHz-30MHz	9kHz	9kHz
Radiated	Peak	30MHz-1GHz	100kHz	100kHz
Radiated	QP	30MHz-1GHz	120kHz	120kHz
Radiated	Peak/Avg	Above 1GHz	1MHz	1MHz

Note: All readings on data pages are taken with the detector in peak mode unless otherwise stated.

UNITS OF MEASUREMENT

Measurements of radiated interference are reported in terms of dBuV/m, at a specified distance. The indicated readings on the spectrum analyzer are converted to dBuV/m by use of appropriate conversion factors. Measurements of conducted interference are reported in terms of dBuV.

TEST EQUIPMENT LIST (EMISSION)

Instrumentation: The following list contains equipment used at C & C Laboratory, Co., Ltd. for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.2-1988 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 10kHz to 1.0 / 2.0 GHz.

Equipment used during the tests:

Open Area Test Site: ☐ # 1 ; ☒ # 3 ; ☐ # 4

Open Area Test Site # 1					
EQUIPMENT TYPE	* MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	HP	8568B	3001A05004	04/16/1999	04/15/2000
S.P.A Display	HP	85662A	3104A18846	04/16/1999	04/15/2000
RF Pre-selector	HP	85685A	2947A01064	04/16/1999	04/15/2000
Q.P Adaptor	HP	85650A	2811A01399	04/16/1999	04/15/2000
Precision Dipole	R&S	HZ-12	846932/0004	06/16/1999	06/16/2000
Precision Dipole	R&S	HZ-13	846556/0008	06/16/1999	06/16/2000
Horn Antenna	EMCO	3115	9602-4659	04/04/1999	04/04/2000
Bilog Antenna	CHASE	CBL6112A	2309	03/14/1999	03/14/2000
Turn Table	EMCO	2081-1.21	N/A	N/A	N/A
Antenna Tower	EMCO	2075-2	9707-2604	N/A	N/A
Controller	EMCO	2090	N/A	N/A	N/A
RF Switch	ANRITSU	MP59B	N/A	N/A	N/A
Site Information	C&C	N/A	N/A	01/23/1999	01/23/2000

Open Area Test Site # 3					
EQUIPMENT TYPE	* MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3261C	71720533	10/27/1998	10/26/1999
Pre-Amplifier	HP	8447D	2944A09173	01/28/1999	01/27/2000
EMI Test Receiver	R&S	ESVS20	838804/004	12/12/1998	12/11/1999
Precision Dipole	R&S	HZ-12	846932/0004	06/06/1999	06/06/2000
Precision Dipole	R&S	HZ-13	846556/0008	06/16/1999	06/16/2000
Horn Antenna	EMCO	3115	9602-4659	04/04/1999	04/04/2000
Bilog Antenna	CHASE	CBL6112A	2179	11/14/1998	11/14/1999
Turn Table	EMCO	2081-1.21	9709-1885	N/A	N/A
Antenna Tower	EMCO	2075-2	9707-2060	N/A	N/A
Controller	EMCO	2090	9709-1256	N/A	N/A
RF Switch	ANRITSU	MP59B	N/A	N/A	N/A
Site Information	C&C	N/A	N/A	01/31/1999	01/31/2000

Open Area Test Site # 4					
EQUIPMENT TYPE	* MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3261C	81720301	SEP/02/1999	SEP/01/2000
Pre-Amplifier	HP	8447F	2944A03748	OCT/22/1998	OCT/21/1999
EMI Test Receiver	R&S	ESVS10	846285/016	DEC/19/1998	DEC/18/1999
Turn Table	Chance most	N/A	N/A	N/A	N/A
Antenna Tower	Chance most	N/A	N/A	N/A	N/A
Controllor	Chance most	N/A	N/A	N/A	N/A
Bilog Antenna	Chase	CBL 6112B	2462	JAN/01/1999	JAN/01/2000
Site NSA	C&C Lab.	N/A	N/A	DEC/27/1998	DEC/27/1999

Conducted Emission Test Site: ☐ # 1 ; ☒ # 3 ; ☐ # 4

Conducted Emission Test Site # 1					
EQUIPMENT TYPE	* MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	HP	8568B	3001A05004	04/16/1999	04/15/2000
S.P.A Display	HP	85662A	3104A18846	04/16/1999	04/15/2000
RF Pre-selector	HP	85685A	2947A01064	04/16/1999	04/15/2000
Q.P Adaptor	HP	85650A	2811A01399	04/16/1999	04/15/2000
LISN	EMCO	3825/2	9106-1809	08/14/1999	08/14/2000
LISN	EMCO	3825/2	9106-1810	08/14/1999	08/14/2000

Conducted Emission Test Site # 3					
EQUIPMENT TYPE	* MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3261A	91720031	03/25/1999	03/24/2000
EMI Test Receiver	R&S	ESHS10	843743/015	12/09/1998	12/08/1999
LISN	R&S	ESH3-Z5	848773/014	10/22/1998	10/21/1999
LISN	EMCO	3825/2	9003-1628	04/29/1999	04/28/2000

Conducted Emission Test Site # 4					
EQUIPMENT TYPE	* MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
EMI Test Receiver	R&S	ESCS30	847793/012	12/19/1998	12/18/1999
LISN	R&S	ESH2-Z5	848773/014	12/04/1998	12/03/1999
LISN	EMCO	3825/2	9003-1628	01/09/1999	01/08/2000

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

TEST EQUIPMENT LIST

For Power Harmonic & Voltage Fluctuation/Flicker Measurement:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH Harmonic & Flicker Tester	PHF 555	080 419-25	Oct. 27, 1998	Oct. 26, 1999

For ESD test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Electrostatic Discharge Simulator	PESD 1600	H710203	Sep. 04, 1999	Sep. 03, 2000

For Radiated Electromagnetic Field immunity Measurement: (ENV 50140 and ENV 50204)

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Maconi /Signal Generator	2022D	119246/003	Aug. 10, 1999	Aug. 10, 2000
M2S / Power Amplifier	A00181/1000	9801-112	N/A	N/A
M2S / Power Amplifier	AC8113/800-250A	9801-179	N/A	N/A
Wandel & Goltormann/ EM-Radiation Meter	EMR-30	L-0013	Dec. 11, 1998	Dec. 11, 1999
Wandel & Goltormann/ E- Field Sensor	TYP-8	H-0014	Dec. 11, 1998	Dec. 11, 1999
EMCO Power Antenna	3141	9712-1083	N/A	N/A

For Fast Transients/Burst test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Fast Transients/Burst Generator	PEFT-JUNIOR	583 333-117	Sep. 03, 1999	Sep. 02, 2000

For CS test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
M2S / Power Amplifier	A00181/1000	9801-112	Jan. 27, 1999	Jan. 26, 2000

For Surge Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Surge Tester	PSURGE 4010	583 334-71	Sep. 03, 1999	Sep. 02, 2000

For Power Frequency Magnetic Field Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
F.W.BELL/ TRIAX ELF Magnetic Field Meter	4090	359194	Oct.08.1998	Oct.07.1999
HAEFELY TRENCH/ Magnetic Field Tester	MAG 100.1	080 938-01	N/A	N/A

For Voltage Dips/Short Interruption and Voltage Variation Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Dips/Interruption and Variations Simulator	PLINE 1610	080 334-05	Sep. 04, 1999	Sep. 03, 2000

SECTION 1 EN 55022 (LINE CONDUCTED & RADIATED EMISSION)

MEASUREMENT PROCEDURE (PRELIMINARY LINE CONDUCTED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022: 1994 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022: 1994.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022: 1994.
- 4) The EUT received AC power through a Line Impedance Stabilization Network (LISN) which supplied power source of 230VAC/50Hz and was grounded to the ground plane.
- 5) All support equipment received power from a second LISN supplying power of 110VAC/60Hz.
- 6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum analyzer connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to analyzer and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the analyzer.
- 7) Analyzer scanned from 150kHz to 30MHz for emissions in each of the test modes. Analyzer settings were stated on the Measuring Instrument Settings page.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) The following test model(s) were scanned during the preliminary test:

Model(s):

1. MIC-3351
2. MIC-3351S

- 10) After the preliminary scan, we found the following test model producing the highest emission level.

Model: 2

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

MEASUREMENT PROCEDURE (FINAL LINE CONDUCTED EMISSION TEST)

- 1) EUT and support equipment was set up on the test bench as per step 10 of the preliminary test.
- 2) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less -2dB to the A.V. limit in peak mode, then the emission signal was re-checked using a Quasi-Peak and Average detector.
- 3) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. MHz	Q.P. Raw dBuV	Average Raw dBuV	Q.P. Limit dBuV	Average Limit dBuV	Q.P. Margin dB	Average Margin dB	Note
x.xx	43.95	---	56	46	-12.05	-2.05	L1

Freq.	= Emission frequency in MHz
Limit dBuV	= Limit stated in standard
Margin dB	= Reading in reference to limit
Note	= Current carrying line of reading
“---“	= The emission level complied with the Average limits, with at least 2dB margin, so no further recheck.

LINE CONDUCTED EMISSION LIMIT

Frequency	Maximum RF Line Voltage	
	Q.P.	AVERAGE
150kHz-500kHz	79dBuV	66dBuV
500KHz-30MHz	73dBuV	60dBuV

Note: The lower limit shall apply at the transition frequency.

MEASUREMENT PROCEDURE (PRELIMINARY RADIATED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55022: 1994 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022: 1994.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022: 1994.
- 4) The EUT received 230VAC/50Hz power source from the outlet socket under the turntable. All support equipment received 110VAC/60Hz power from another socket under the turntable.
- 5) The antenna was placed at some given distance away from the EUT as stated in EN 55022: 1994. The antenna connected to the analyzer via a cable and at times a pre-amplifier would be used.
- 6) The analyzer quickly scanned from 30MHz to 1000MHz. Analyzer settings were stated on the Measuring Instrument Settings page. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 7) The following test model(s) were scanned during the preliminary test:

Model(s):

- 1. MIC-3351**
- 2. MIC-3351S**

- 8) After the preliminary scan, we found the following test model producing the highest emission level.

Model: 2

Then, the EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for final testing.

MEASUREMENT PROCEDURE (FINAL RADIATED EMISSION TEST)

- 1) EUT and support equipment were set up on the turntable as per step 8 of the preliminary test.
- 2) The analyzer scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 3) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.
- 4) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. (MHz)	Raw Data (dB)	Corr. Factor (dBuV)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
xx.xx	14.0	11.2	26.2	30	-3.8

Freq.	= Emission frequency in MHz
Raw Data (dB)	= Uncorrected Analyzer / Receiver reading
Corr. Factor (dBuV)	= Correction factors of antenna factor and cable loss
Emiss. Level	= Raw reading converted to dBuV and CF added
Limit dBuV/m	= Limit stated in standard
Margin dB	= Reading in reference to limit

RADIATED EMISSION LIMIT

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m/ Q.P.)
30-230	10	40
230-1000	10	47

Note: The lower limit shall apply at the transition frequency.

BLOCK DIAGRAM OF TEST SETUP

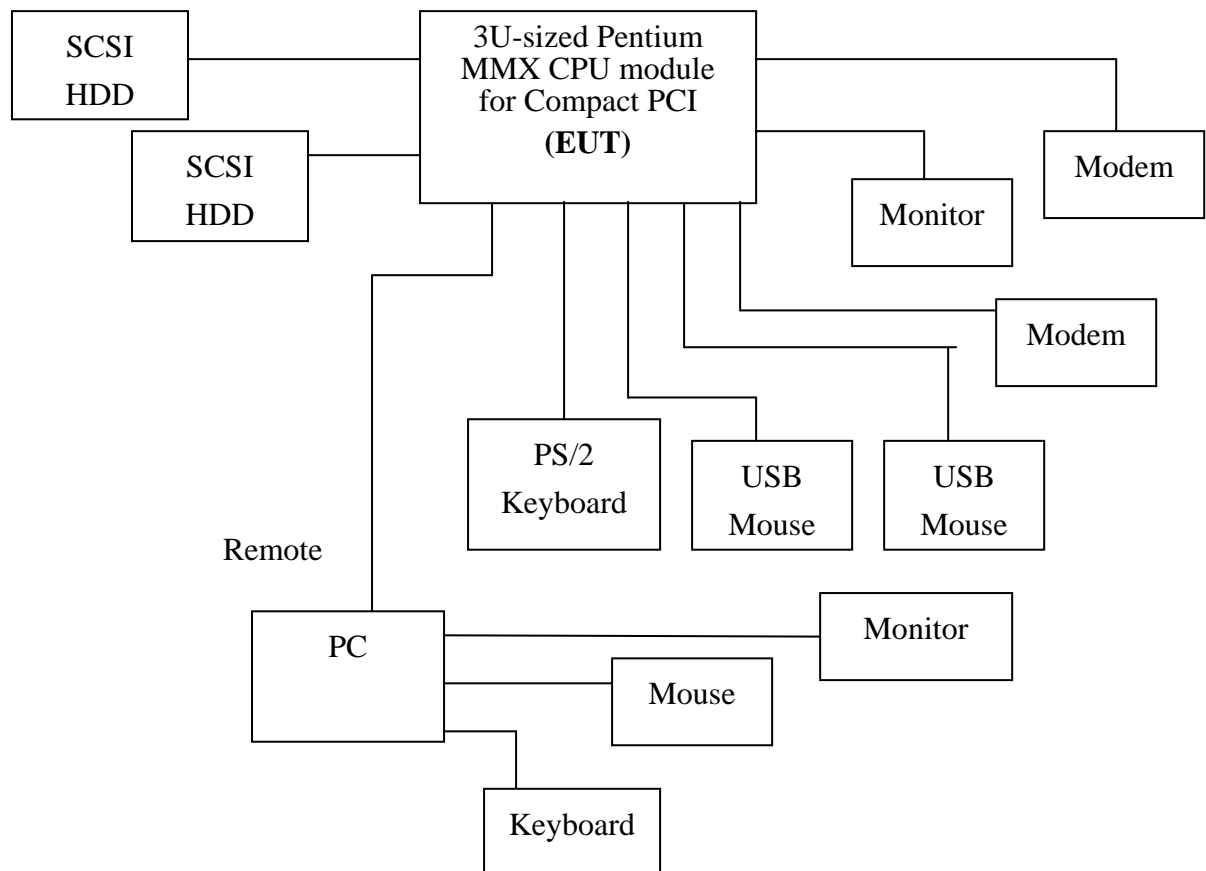
System Diagram of Connections between EUT and Simulators

EUT: 3U-sized Pentium MMX CPU module for Compact PCI

Trade Name: ADVANTECH

Model Number: MIC-3351S

Power Cord: Shielded, 1.8m



SUMMARY DATA

(LINE CONDUCTED TEST)

Model Number: MIC-3351S

Location: Site # 3

Tested by: Tony Tsai

Test Mode: Full System

Test Results: Passed

Temperature: 27°C

Humidity: 58%RH

(The chart below shows the highest readings taken from the final data)

FREQ MHz	Q.P. RAW dBuV	AVG RAW dBuV	Q.P. Limit dBuV	AVG Limit dBuV	Q.P. Margin dB	AVG Margin dB	NOTE
0.227	47.3	---	79.0	66.0	-31.7	---	L1
0.231	46.8	---	79.0	66.0	-32.2	---	L1
0.338	38.1	---	79.0	66.0	-40.9	---	L1
0.565	36.3	---	73.0	60.0	-36.7	----	L1
0.790	32.9	---	73.0	60.0	-40.1	---	L1
0.906	31.6	---	73.0	60.0	-41.4	---	L1
0.227	44.6	---	79.0	66.0	-34.4	---	L2
0.231	43.7	---	79.0	66.0	-35.3	---	L2
0.338	37.5	---	79.0	66.0	-41.5	---	L2
0.535	34.0	---	73.0	60.0	-14.2	---	L2
0.790	32.9	---	73.0	60.0	-40.1	---	L2
0.906	31.9	---	73.0	60.0	-41.1	---	L2

L1 = Line One (Hot side) / L2 = Line Two (Neutral side)

****NOTE: “---” denotes the emission level was or more than 2dB below the Average limit, so no re-check anymore.**

SUMMARY DATA

(RADIATED EMISSION TEST)

Model Number: MIC-3351S

Location: Site # 3

Tested by: Tony Tsai

Test Mode: Full System

Polar: Vertical -- 10m

Test Results: Passed

Temperature: 26°C

Humidity: 60%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dB)	Corr. Factor (dBuV)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
66.79	26.8	7.2	34.0	40.0	-6.0
133.68	19.5	14.7	34.2	40.0	-5.8
200.00	22.5	12.3	34.8	40.0	-5.2
467.69	16.7	22.4	39.1	47.0	-7.9
601.40	16.3	25.5	41.8	47.0	-5.2
735.04	18.5	26.4	44.9	47.0	-2.1

SUMMARY DATA

(RADIATED EMISSION TEST)

Model Number: MIC-3351S

Location: Site # 3

Tested by: Tony Tsai

Test Mode: Full System

Polar: Horizontal -- 10m

Test Results: Passed

Temperature: 26°C

Humidity: 60 %RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dB)	Corr. Factor (dBuV)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
167.03	22.4	12.9	37.3	40.0	-2.7
334.07	23.4	19.4	42.8	47.0	-4.2
434.23	22.0	22.4	44.4	47.0	-2.6
467.72	20.2	23.0	43.2	47.0	-3.8
668.25	17.9	26.4	44.3	47.0	-2.7
734.98	17.6	26.2	43.8	47.0	-3.2

SECTION 2 EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS & VOLTAGE FLUCTUATION/FLICKER)

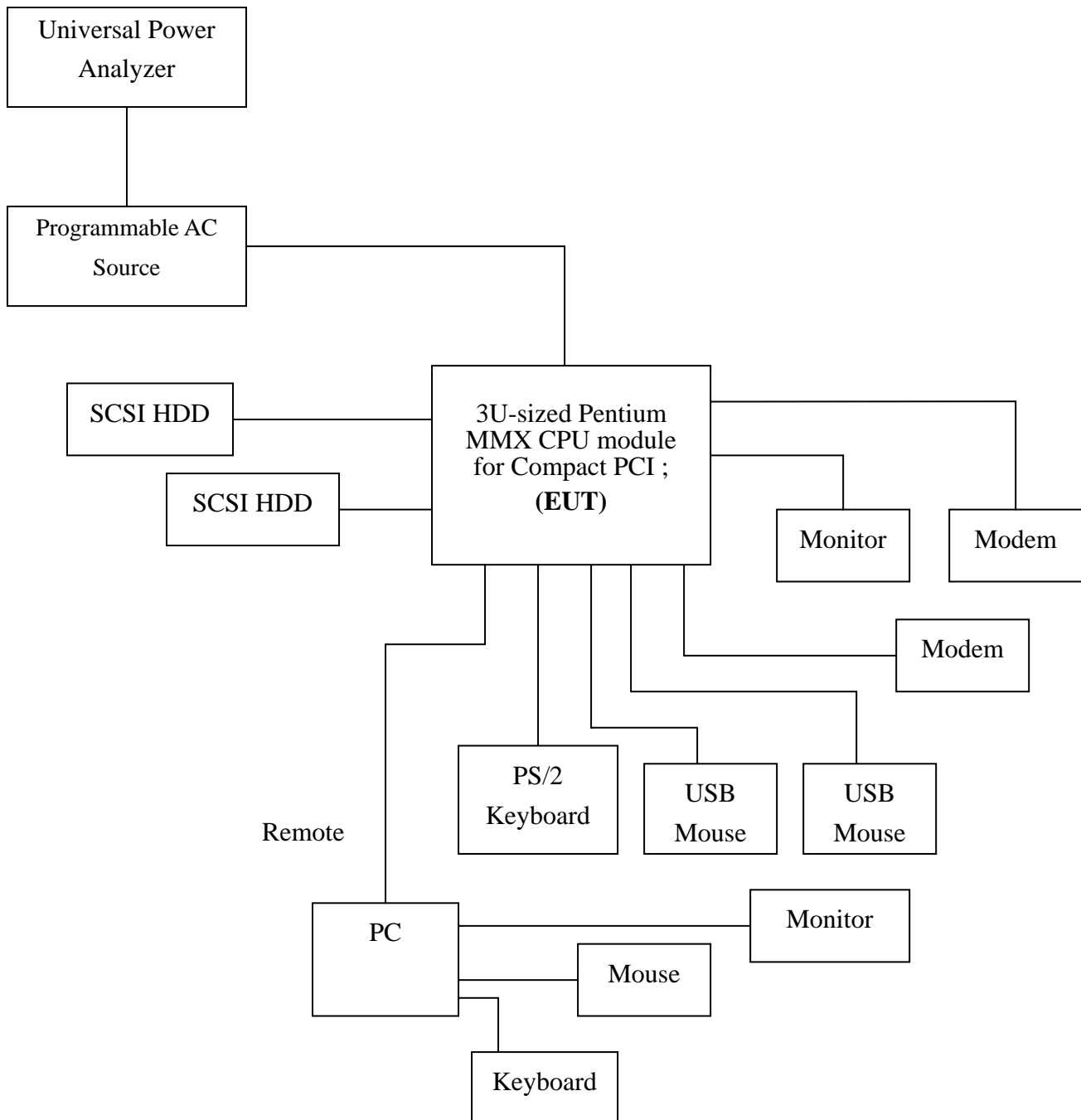
POWER HARMONICS MEASUREMENT

Port : AC mains
Basic Standard : EN 61000-3-2 (1995)
Limits : ☒ CLASS A ; ☐ CLASS D
Temperature : 27°C
Humidity : 58%

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port : AC mains
Basic Standard : EN 61000-3-3 (1995)
Limits : §5 of EN 61000-3-3
Temperature : 27°C
Humidity : 58%

Block Diagram of Test Setup:



Result:

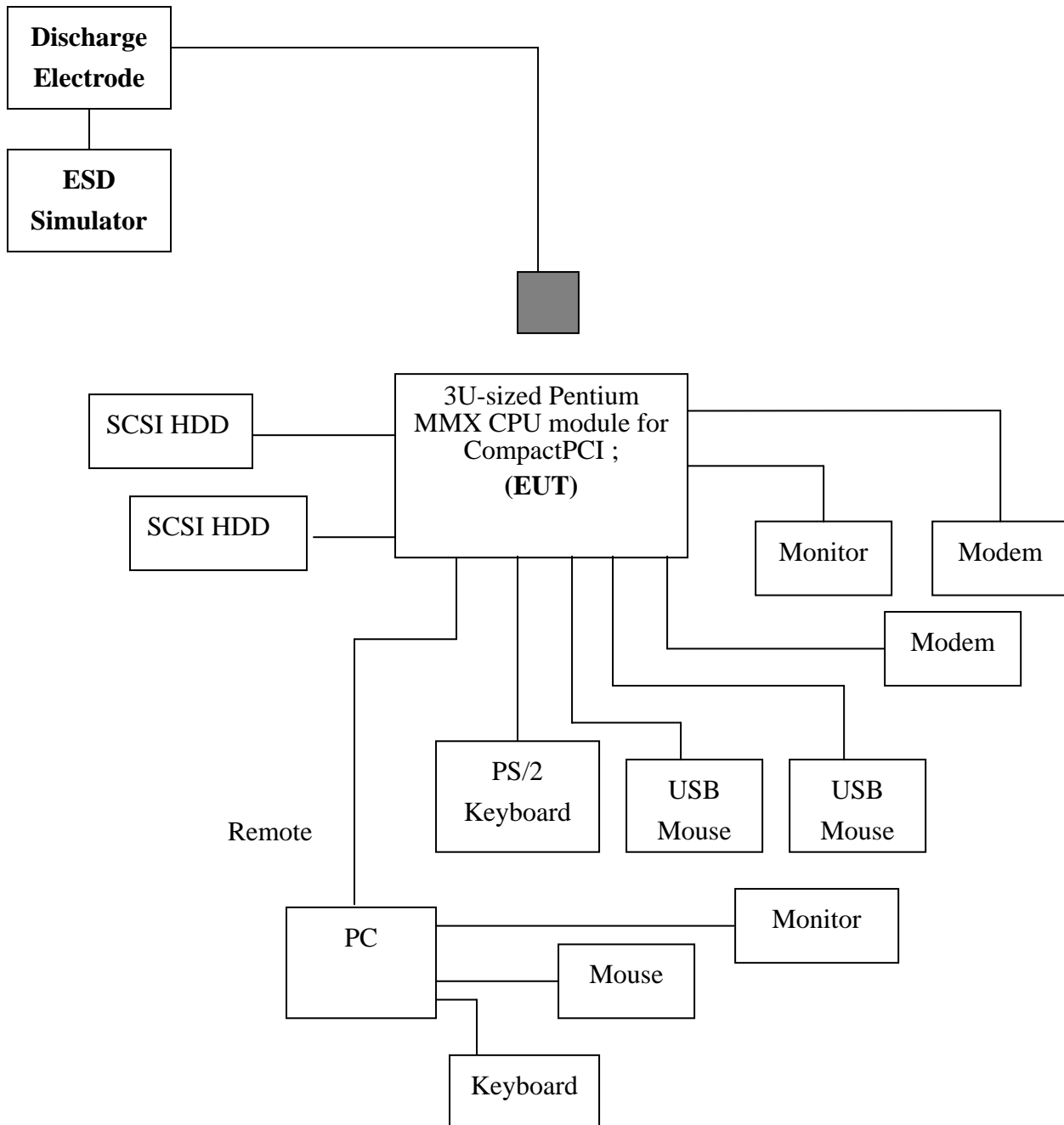
Please see the attached test data.

SECTION 3 EN 61000-4-2 (ELECTROSTATIC DISCHARGE)

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure
Basic Standard : EN 61000-4-2
Requirements : $\pm 8\text{kV}$ (Air Discharge)
 $\pm 4\text{kV}$ (Contact Discharge)
 $\pm 4\text{kV}$ (Indirect Discharge)
Performance Criteria : B (Standard Required)
Temperature/Humidity: 26°C / 60%

Block Diagram of Test Setup:



Test Procedure:

The electrostatic discharges were applied as follows:

Amount of Discharges	Voltage	Coupling	Result (Pass/Fail)
≥ 10 /Point	$\pm 8KV$	Air Discharge	Pass
≥ 10 /Point	$\pm 4KV$	Contact Discharge	Pass
≥ 10 /Point	$\pm 4KV$	Indirect Discharge HCP	Pass
≥ 10 /Point	$\pm 4KV$	Indirect Discharge VCP (Front)	Pass
≥ 10 /Point	$\pm 4KV$	Indirect Discharge VCP (Left)	Pass
≥ 10 /Point	$\pm 4KV$	Indirect Discharge VCP (Back)	Pass
≥ 10 /Point	$\pm 4KV$	Indirect Discharge VCP (Right)	Pass

** The tested points to EUT, please refer to attached pages.

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

****Observation:** No any function degraded during the test.

The Tested Points of EUT



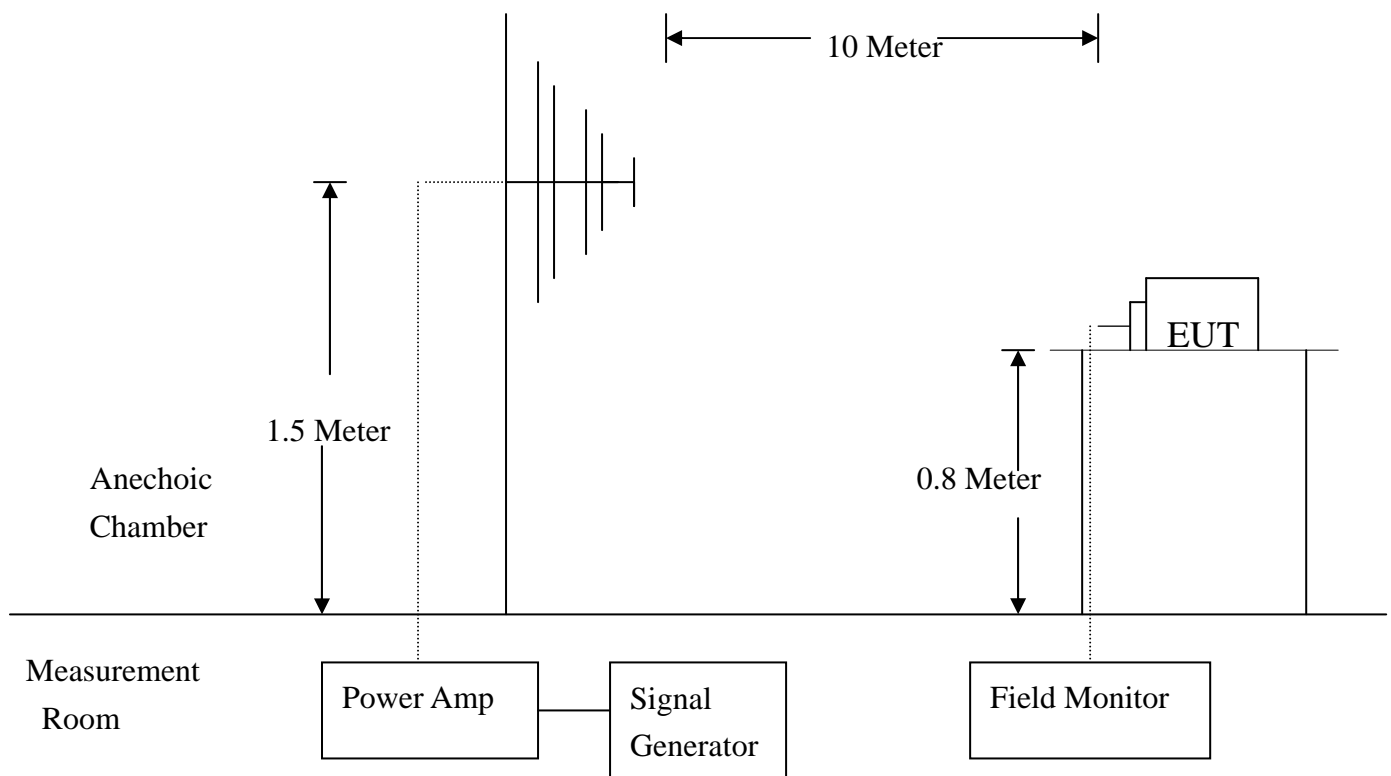
SECTION 4 ENV 50140 (RADIATED ELECTROMAGNETIC FIELD)

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port	: Enclosure
Basic Standard	: ENV 50140
Requirements	: 10 V/m / Modulated
Performance Criteria	: A (Standard Required)
Temperature	: 26°C
Humidity	: 60%

Block Diagram of Test Setup:

Same as Section 1 EN 55022 Test Setup:



Test Procedure:

Frequency Range : 80MHz-1000MHz

Frequency Step : 1% of fundamental

Dwell Time : 1 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	10V	Yes	H	0	Pass
80-1000	10V	Yes	V	0	Pass
80-1000	10V	Yes	H	90	Pass
80-1000	10V	Yes	V	90	Pass
80-1000	10V	Yes	H	180	Pass
80-1000	10V	Yes	V	180	Pass
80-1000	10V	Yes	H	270	Pass
80-1000	10V	Yes	V	270	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

****Observation:** No any function degraded during the test.

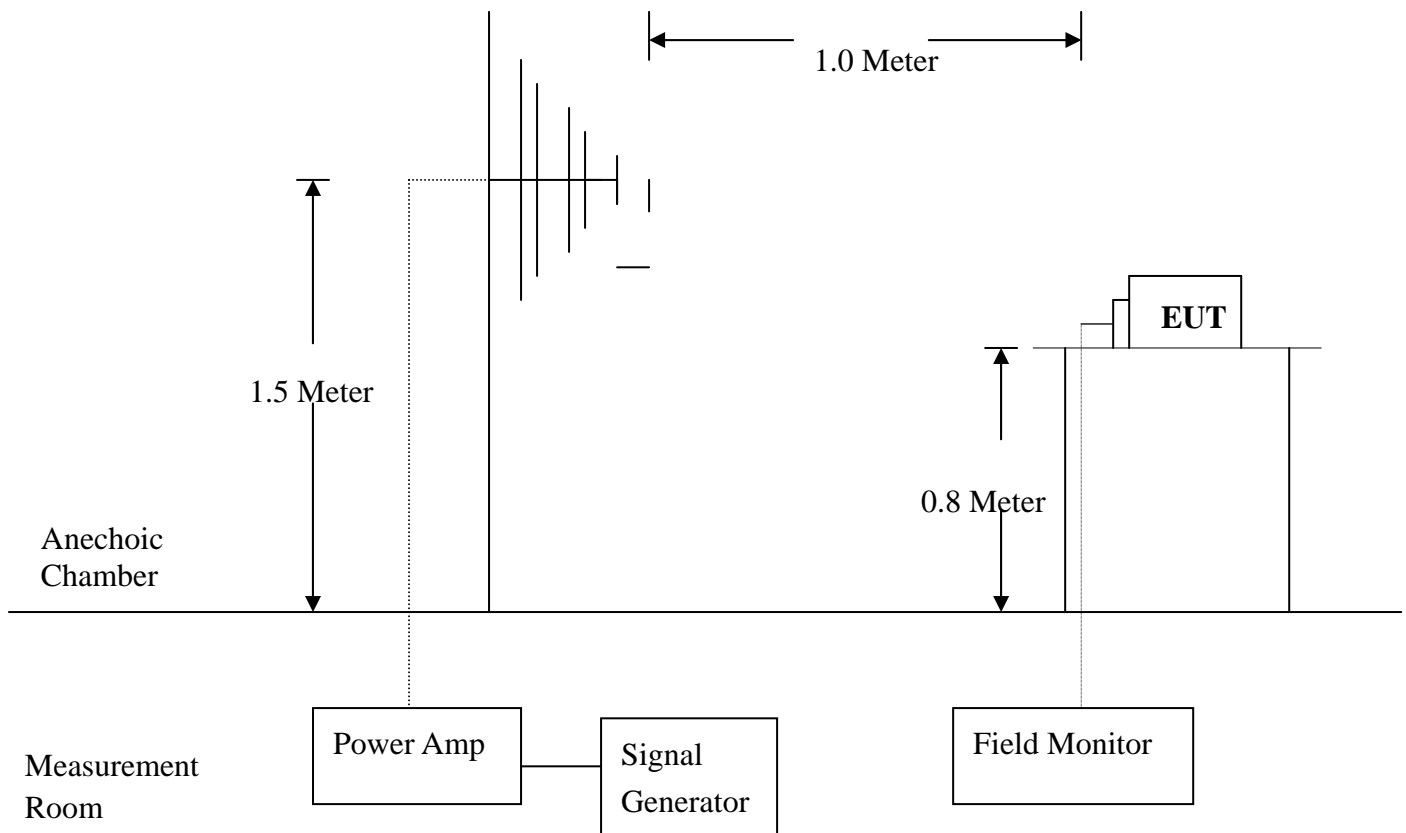
SECTION 5 ENV 50204 (RADIATED ELECTROMAGNETIC FIELD FROM DIGITAL TELEPHONES)

Radiated Electromagnetic Field From Digital Telephones Immunity Test

Port	: Enclosure
Basic Standard	: ENV 50204
Requirements	: 10 V/m, with modulated
Performance Criteria	: A (Standard Required)
Temperature	: 25°C
Humidity	: 57%

Block Diagram of Test Setup:

Same as Section 1 EN 55022 Test Setup:



Test Procedure:

Spot Frequency : 900 MHz \pm 5MHz
Modulated Frequency : 200 Hz
Duty cycle : 50%

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
900	10V	Yes	H	0	Pass
900	10V	Yes	V	0	Pass
900	10V	Yes	H	90	Pass
900	10V	Yes	V	90	Pass
900	10V	Yes	H	180	Pass
900	10V	Yes	V	180	Pass
900	10V	Yes	H	270	Pass
900	10V	Yes	V	270	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

Observation: No any function degraded during the tests.

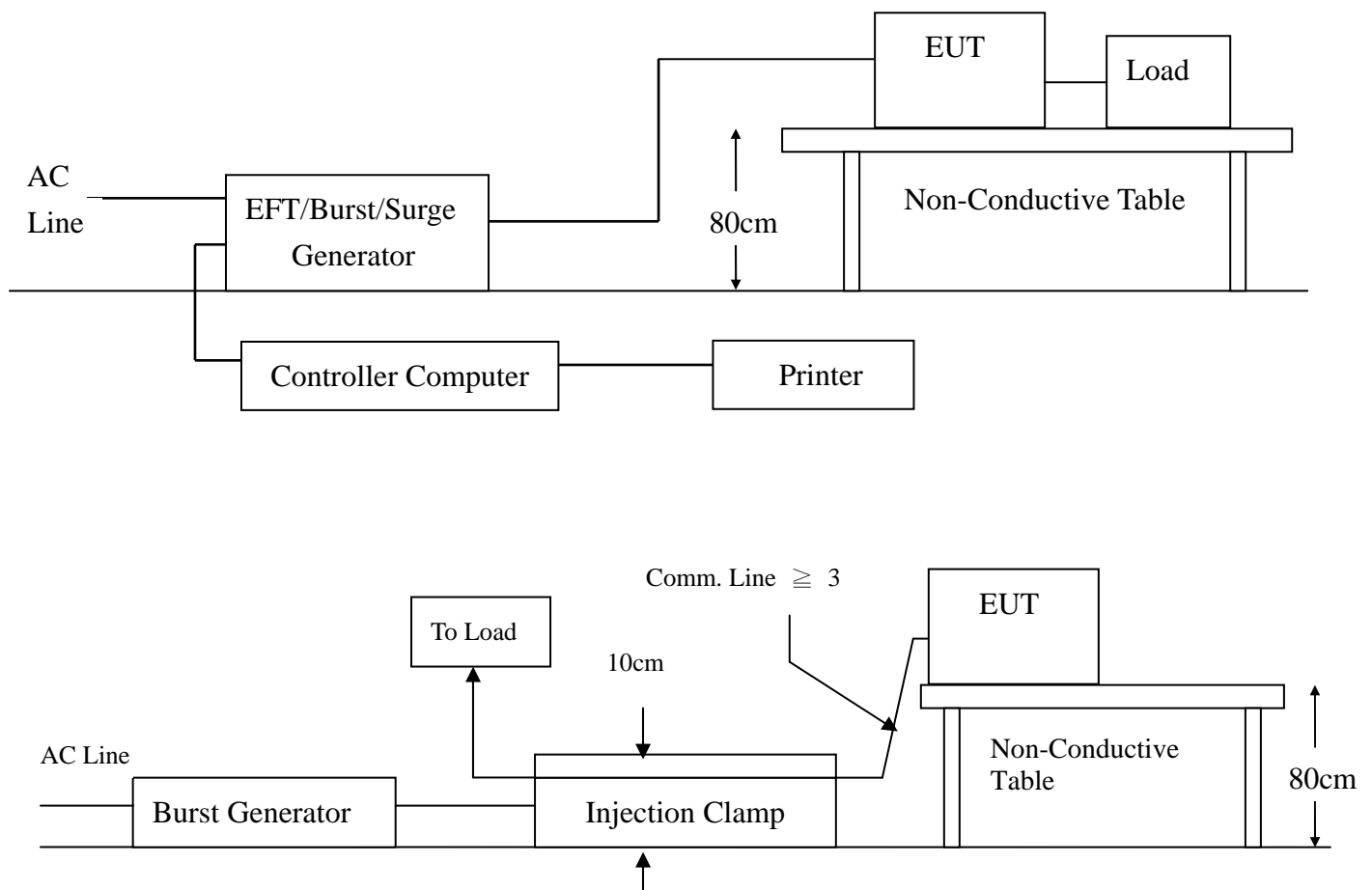
SECTION 6 EN 61000-4-4 (FAST TRANSIENTS/BURST)

FAST TRANSIENTS/BURST IMMUNITY TEST

Port	: On Power Port and Data Cable
Basic Standard	: EN 61000-4-4
Requirements	: $\pm 2\text{kV}$ to Power Port $\pm 1\text{kV}$ to Data Cable
Performance Criteria	: B (Standard Required)
Temperature	: 26°C
Humidity	: 60%

Block Diagram of Test Setup:

Same as section1 EN 55022 Test Setup:



Test Procedure:

Impulse Frequency: 5kHz

Tr/Tn: 5/50ns

Burst Duration: 15ms

Burst Period: 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L1	±2	Direct	Pass
N	±2	Direct	Pass
PE	±2	Direct	Pass
L1+N	±2	Direct	Pass
L1+PE	±2	Direct	Pass
N+PE	±2	Direct	Pass
L1+N+PE	±2	Direct	Pass
LAN Port	±1	Clamp	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

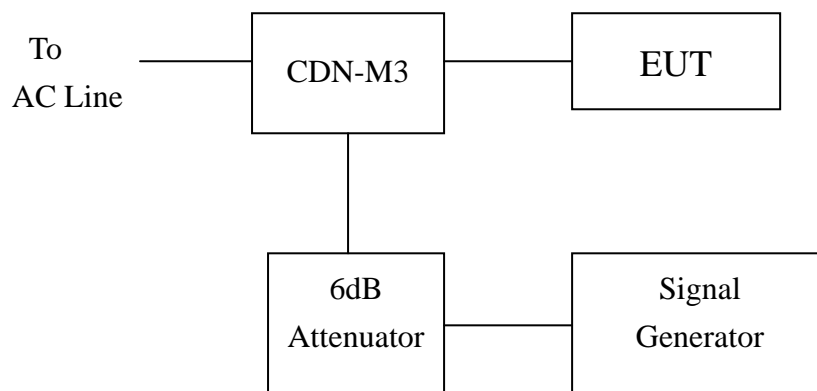
****Observation:** No any function degraded during the tests.

SECTION 7 ENV 50141 (CONDUCTED DISTURBANCE/INDUCED BY RADIO-FREQUENCY FIELD)

Port : Power cord
Basic Standard : ENV 50141
Requirements : 10 V with modulated
Injection Method : CDN-M3
Performance Criteria : A
Temperature : 26°C
Humidity : 58%

Block Diagram of Test Setup:

Same as Section 1 EN 55022 Test Setup:



Test Procedure:

Frequency Range : 0.15MHz-80MHz
Frequency Step : 1% of fundamental
Dwell Time : 1 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	10V	Yes	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

****Observation:** No any function degraded during the tests.

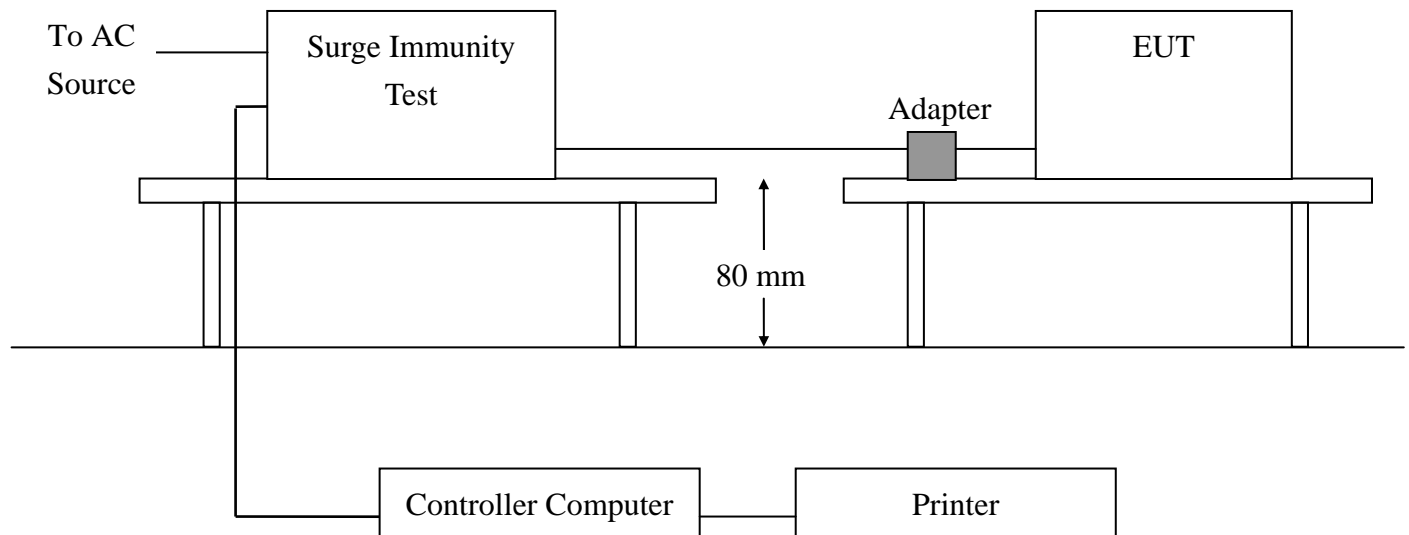
SECTION 8 EN 61000-4-5 (SURGE IMMUNITY)

SURGE IMMUNITY TEST

Port	: Power Cord
Basic Standard	: EN 61000-4-5
Requirements	: $\pm 1\text{kV}$ (Line to Line) : $\pm 2\text{kV}$ (Line to Ground)
Performance Criteria	: A (Standard require)
Temperature	: 27°C
Humidity	: 60%

Block Diagram of Test Setup:

Same as Section 1 EN 55022 Test Setup:



Test Procedure:

Voltage Waveform : 1.2/50 μ s
Current Waveform : 8/20 μ s
Polarity : Positive/Negative
Phase angle : 0° , 90° , 270°
Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

****Observation:** No any function degraded during the tests.

SECTION 9 EN 61000-4-11 (VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS)

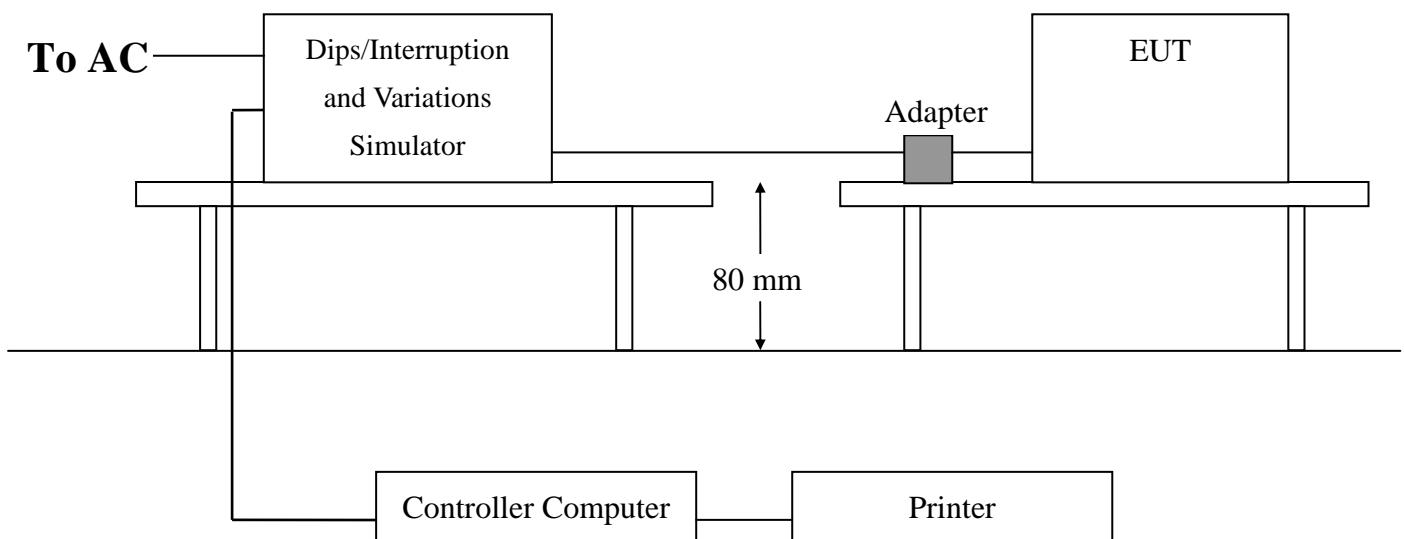
VOLTAGE DIPS / SHORT INTERRUPTIONS

Port : AC mains
Basic Standard : EN 61000-4-11 (1994)
Requirement : PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Test Level % U_T	Voltage Dip and Interrupt Reduction(%)	Duration (ms)	Performance Criteria
<0	>95	5000	C
70	30	10	B
40	60	100	C

Test Interval : Min. 10 sec.
Temperature : 27°C
Humidity : 58%

Block Diagram of Test Setup:



Test Procedure:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum
(Between each test event)

Test Level % U_T	Voltage Dip and Interrupt Reduction(%)	Duration (ms)	Observation	Meet Performance Criteria
<0	>95	5000	EUT shot down but can be auto recovered,as the events disappears	C
70	30	10	Normal	A
40	60	100	Normal	A

Performance & Result:

- Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

Test Result : PASS

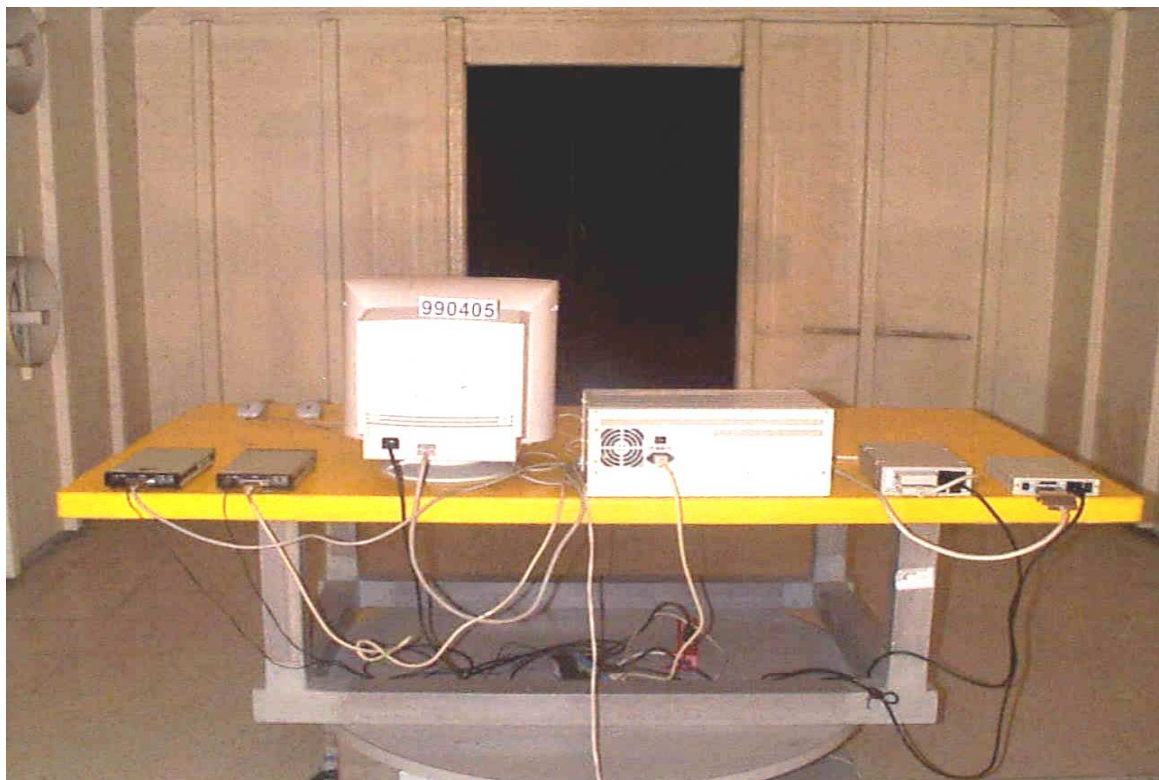
APPENDIX 1

PHOTOGRAPHS OF TEST SETUP

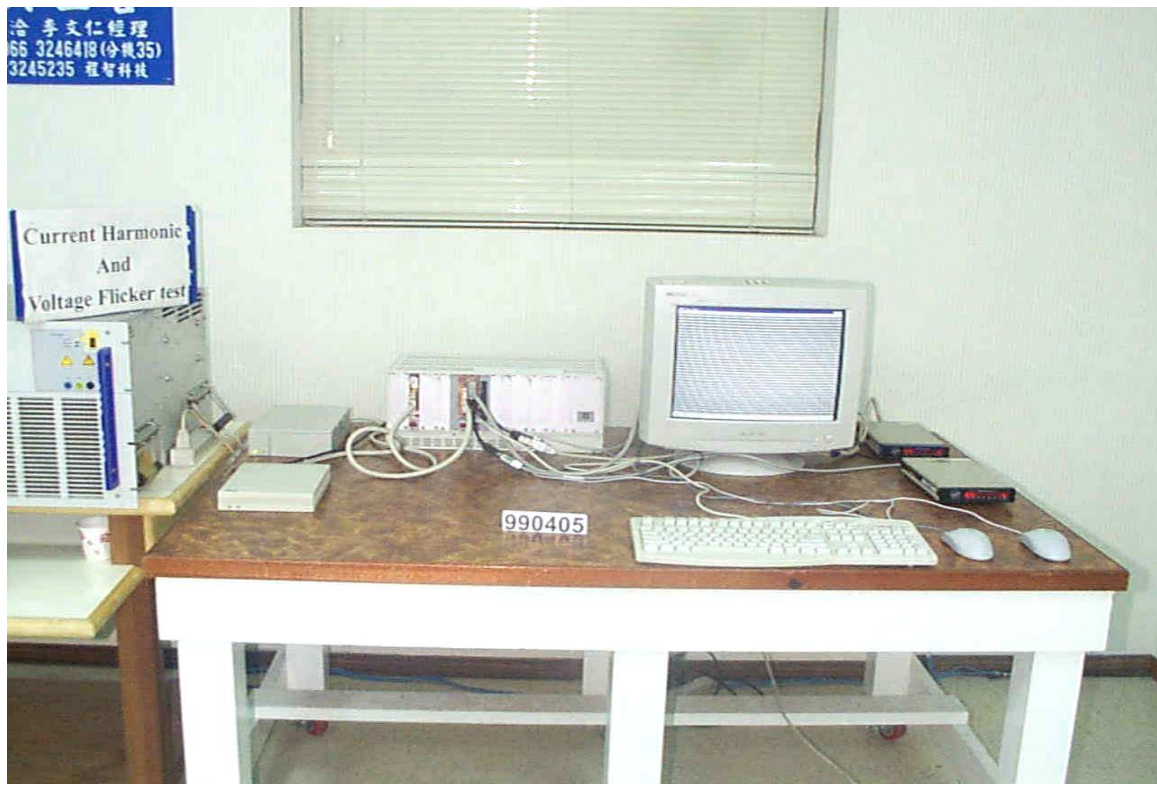
LINE CONDUCTED EMISSION TEST (EN 55022)



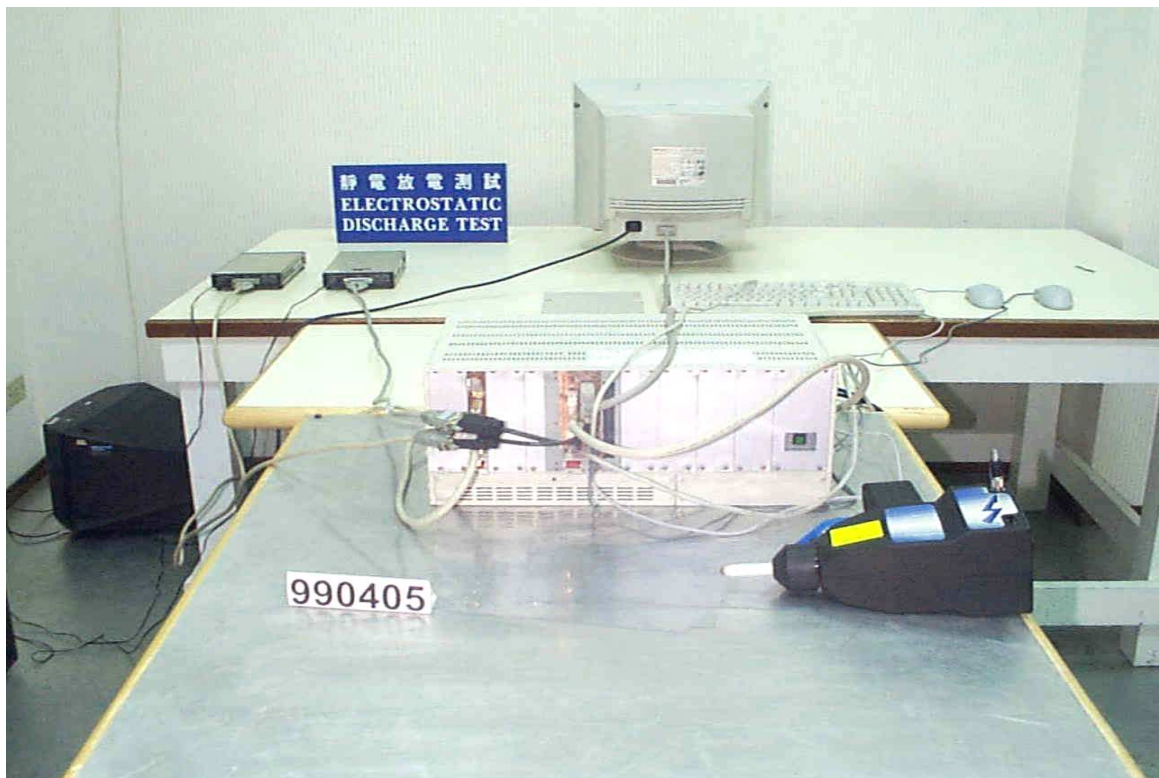
RADIATED EMISSION TEST (EN 55022)



POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST (EN 61000-3-2, EN 61000-3-3)



ELECTROSTATIC DISCHARGE TEST (EN 61000-4-2)



RADIATED ELECTROMAGNETIC FIELD (ENV 50140 & ENV 50204)



FAST TRANSIENTS/BURST TEST (EN 61000-4-4)



CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST (ENV 50141)



SURGE IMMUNITY TEST (EN 61000-4-5)



VOLTAGE DIPS / INTERRUPTION TEST (EN 61000-4-11)



APPENDIX 2

PHOTOGRAPHS OF EUT

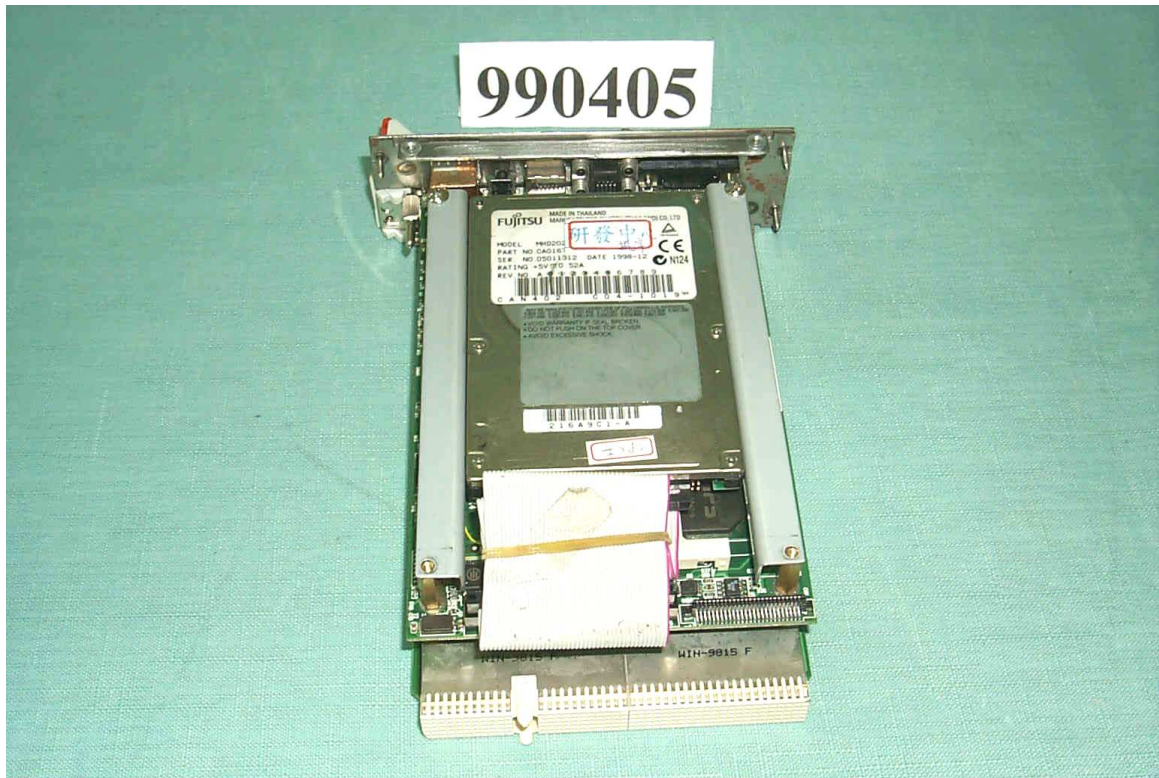
Front View of EUT



Back View of EUT



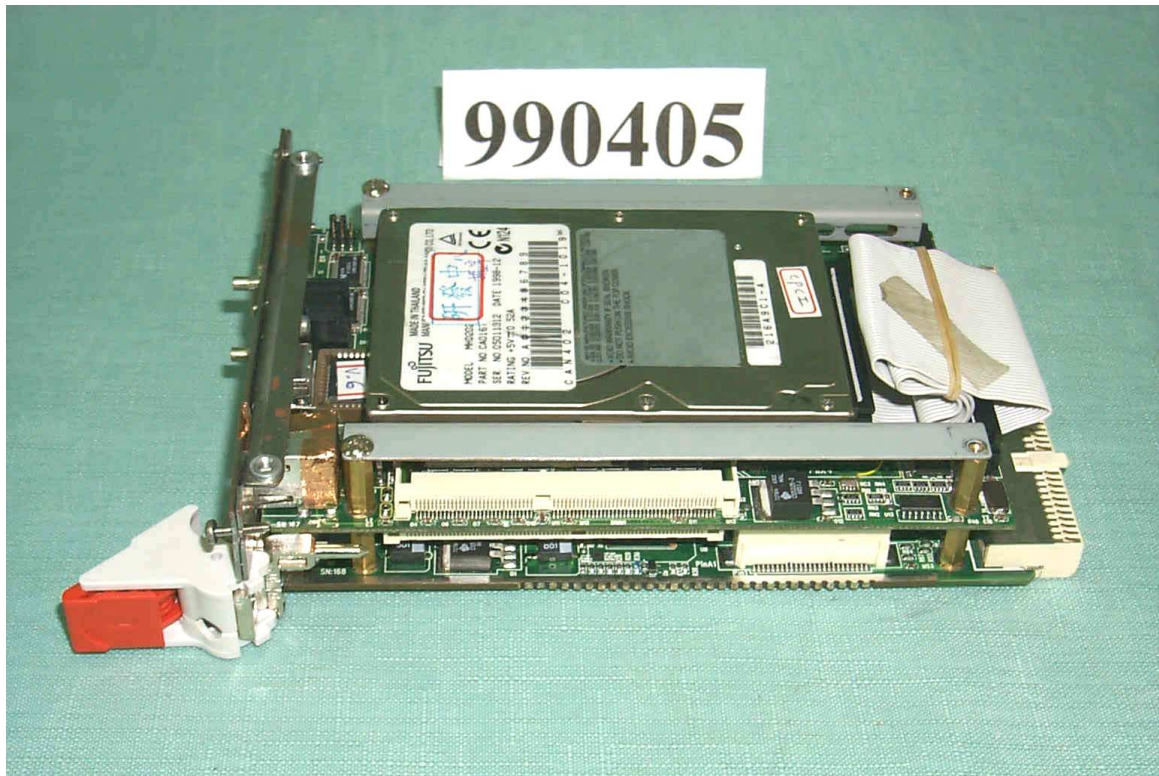
Front View of CPU Card



Back View of CPU Card



Right View of CPU Card



Left View of CPU Card



I/O Port of CPU Card

